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| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 09/900,584 | NAKANO, TAKEHIKO | |
| Examiner | | Art Unit | David G. Cervetti | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Número-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-5,553,143 A | 09-1996 | Ross et al. | 705/59 |
| * | B | US-5,892,900 A | 04-1999 | Ginter et al. | 726/26 |
| * | C | US-5,905,860 A | 05-1999 | Olsen et al. | 726/27 |
| * | D | US-5,915,019 A | 06-1999 | Ginter et al. | 705/54 |
| * | E | US-6,189,146 B1 | 02-2001 | Misra et al. | 717/177 |
| * | F | US-6,343,280 B1 | 01-2002 | Clark, Jonathan | 705/55 |
| * | G | US-6,477,649 B2 | 11-2002 | Kambayashi et al. | 726/27 |
| * | H | US-6,519,571 B1 | 02-2003 | Guheen et al. | 705/14 |
| * | I | US-2003/0120611 A1 | 06-2003 | Yoshino et al. | 705/67 |
| * | J | US-6,574,612 B1 | 06-2003 | Baratti et al. | 705/59 |
| * | K | US-2003/0191946 A1 | 10-2003 | Auer et al. | 713/182 |
| * | L | US-6,785,713 B1 | 08-2004 | Freeman et al. | 709/208 |
| * | M | US-6,772,340 B1 | 08-2004 | Peinado et al. | 713/168 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

| | | | |
|-----------------------------------|--|-------------------------|---|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination |
| | | 09/900,584 | NAKANO, TAKEHIKO |
| Examiner | | Art Unit | Page 2 of 2 |
| David G. Cervetti | | 2136 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-6,873,975 B1 | 03-2005 | Hatakeyama et al. | 705/51 |
| * | B | US-6,891,953 B1 | 05-2005 | DeMello et al. | 380/277 |
| * | C | US-6,922,724 B1 | 07-2005 | Freeman et al. | 709/223 |
| * | D | US-6,950,941 B1 | 09-2005 | Lee et al. | 713/193 |
| * | E | US-7,103,574 B1 | 09-2006 | Peinado et al. | 705/51 |
| * | F | US-7,136,838 B1 | 11-2006 | Peinado et al. | 705/59 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
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| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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